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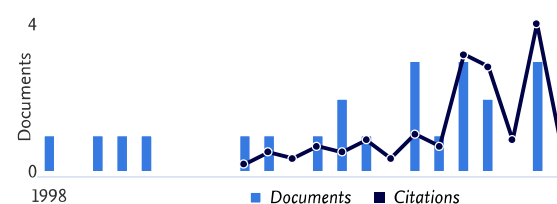
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Defect engineering using microwave processing in SiC and GaAs

Olikh, O., Lytvyn, P.

*Semiconductor Science and Technology*, 2022, 37(7), 075006

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Intensification of iron–boron complex association in silicon solar cells under acoustic wave action

Olikh, O., Kostylyov, V., Vlasuk, V., Korkishko, R., Chupryna, R.

*Journal of Materials Science: Materials in Electronics*, 2022, 33(16), pp. 13133–13142

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Estimation for iron contamination in Si solar cell by ideality factor: Deep neural network approach

Olikh, O., Lozitsky, O., Zavorodnii, O.

*Progress in Photovoltaics: Research and Applications*, 2022, 30(6), pp. 648–660

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Experimental investigation and theoretical modeling of textured silicon solar cells with rear metallization

Sachenko, A.V., Kostylyov, V.P., Korkishko, R.M., ...Dverniov, B.F., Chernenko, V.V.

*Semiconductor Physics, Quantum Electronics and Optoelectronics*, 2022, 25(3), pp. 331–341

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Features of FeB pair light-induced dissociation and repair in silicon n<sup>+</sup>-p-p<sup>+</sup> structures under ultrasound loading

Olikh, O., Kostylyov, V., Vlasuk, V., ...Olikh, Y., Chupryna, R.

*Journal of Applied Physics*, 2021, 130(23), 235703

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*International Conference on Electrical, Computer, Communications and Mechatronics Engineering, ICECCME 2021*, 2021

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*Journal of Electronic Materials*, 2020, 49(8), pp. 4524–4530

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## Influence of $\gamma$ -irradiation and ultrasound treatment on current mechanism in Au-SiO<sub>2</sub>-Si structure

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*Solid-State Electronics*, 2020, 165, 107712

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## Modeling of ideality factor value in N<sup>+</sup>-p-p<sup>+</sup>-Si structure

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Olikh, O.Ya., Zavhorodnii, O.V.

*Journal of Physical Studies*, 2020, 24(4), pp. 1–8, 4701

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*Superlattices and Microstructures*, 2019, 136, 106309

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*Journal of Electronic Materials*, 2018, 47(8), pp. 4370–4378

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*Superlattices and Microstructures*, 2018, 117, pp. 173–188

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Olikh, O.Y., Gorb, A.M., Chupryna, R.G., Pristay-Fenenkov, O.V.

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Ya Olikh, O., Voitenko, K.V., Burbelo, R.M., Olikh, Ja.M.

*Journal of Semiconductors*, 2016, 37(12), 122002

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*Ultrasonics*, 2016, 66, pp. 1–3

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Olikh, O.Y.

*Ultrasonics*, 2015, 56, pp. 545–550

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Lysyuk, I.O., Olikh, Y.M., Olikh, O.Y., Beketov, G.V.

*Ukrainian Journal of Physics*, 2014, 59(1), pp. 50–57

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